



FITCH EVEN TABIN & FLANNERY  
INTELLECTUAL PROPERTY LAW | EST. IN 1859

IFW

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November 13, 2006

Commissioner of Patents  
U.S. Patent and Trademark Office  
Customer Service Window  
**MAIL STOP Amendment**  
Randolph Building  
401 Dulany Street  
Alexandria, VA 22314

Re: Filing of Information Disclosure Statement  
Appl. No.: 10/549,680  
Filed: September 19, 2005  
Title: **High Homogeneity Silica Glass Prepared Through A Sol-Gel Procedure**  
Inventor(s): Fulvio COSTA, *et al.*  
Atty. Dkt.: 7601/84392

Sir:

The following documents are being forwarded for appropriate action by the U.S. Patent and Trademark Office:

1. Information Disclosure Statement;
2. PTO/SB/08a;
3. References: B1 and C1-C2.


The Commissioner is hereby authorized to charge any fee deficiency with respect to this filing and any other fee required in connection with the present case, or credit any overpayment, to our Deposit Account No. 06-1135 under Order No. 7601/84392.

Commissioner of Patents  
November 13, 2006  
Page 2

It is respectfully requested that the enclosed postcard be stamped with the date the enclosed documents are received by the PTO and that it be returned as soon as possible.

Respectfully submitted,

FITCH, EVEN, TABIN & FLANNERY

  
\_\_\_\_\_  
Michael A. Sanzo  
Attorney for Applicant  
Registration No. 36,912

MAS/crh  
Enclosures



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of:

Fulvio COSTA, *et al.*

Appl. No.: 10/549,680

Filed: September 19, 2005

For: **High Homogeneity Silica Glass Prepared  
Through a Sol-Gel Procedure**

Art Unit: 1731

Examiner: Not Yet Assigned

Atty. Dkt.: 7601/84392

**Information Disclosure Statement**

**MAIL STOP - AMENDMENT**

Commissioner of Patents  
U.S. Patent and Trademark Office  
P.O. Box 1450  
Arlington, Virginia 22131-1450

Sir:

Submitted herewith is a listing of documents known to Applicants and/or their attorney in compliance with the requirements of 37 C.F.R. § 1.56. Some of these references were cited in an International Search Report dated July 5, 2004 in the corresponding international application, a copy of which is enclosed. Copies of the listed documents, with the exception of United States patent references, are also enclosed.

Applicants do not waive any rights to appropriate action to establish patentability over any of the listed documents should they be applied as references against the claims of the present application. This statement should not be construed as a representation that more material information does not exist or that an exhaustive search of the relevant art has been made.

Consideration of the cited documents and making the same of record in the prosecution of the above-captioned application are respectfully requested.

Applicants do not believe any fee is due for the submission of this Information Disclosure Statement. However, the Commissioner is hereby authorized to charge any fee deficiency to our Deposit Account No. 06-1135 under Order No. 7601/84392.

Respectfully submitted,

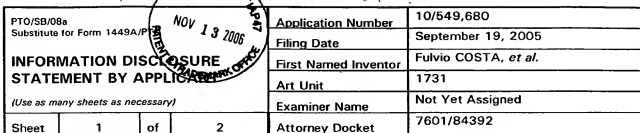
FITCH, EVEN, TABIN & FLANNERY

By



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Attorney for Applicants

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Examiner Initials *	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code?			
/QSD/	A1	5,068,208	11-26-1991	HAUN, <i>et al.</i>	
/QSD/	A2	5,063,179	11-05-1991	MENASHI, <i>et al.</i>	
/QSD/	A3	4,681,615	07-21-1987	TOKI, <i>et al.</i>	
/QSD/	A4	6,360,564	03-26-2002	CORNELIUS, <i>et al.</i>	
	A5				
	A6				
	A7				
	A8				
	A9				
	A10				

Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>2</sup>
		Country Code <sup>3</sup> .Number <sup>4</sup> .Kind Code <sup>5</sup>	MM-DD-YYYY			
/QSD	B1	EP 0 310 486	03-18-1992			
Examiner Signature	/Queenie Dehghan/			Date Considered	10/17/2008	

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kind Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

PTO/SB/08b Substitute for Form 1449B/PTO				Application Number		10/549,680	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				Filing Date		September 19, 2005	
				First Named Inventor		Fulvio COSTA, <i>et al.</i>	
				Art Unit		1731	
				Examiner Name		Not Yet Assigned	
Sheet		2		of		2	
				Attorney Docket		7601/84392	
<b>NON PATENT LITERATURE DOCUMENTS</b>							
Examiner Initials*	Cite No. †	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					T <sup>2</sup>
/QSD/	C1	International Search Report Dated July 5, 2004					
/QSD/	C2	T.Y. TSENG, et al., "Various Atmosphere Effects on Sintering Of Compacts of SiO <sub>2</sub> Microspheres", Journal of Materials Science 21:3615-3624 (1986)					
Examiner Signature	/Queenie Dehghan/				Date Considered	10/17/2008	

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

† Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.